

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Mehrdad Nikoonahad

Title: Optical System for Measuring Samples Using Short Wavelength Radiation

Application No.: 10/718,126 Filing Date: November 19, 2003

Examiner: Pham, Hoa Q. Group Art Unit: 2886

Docket No.: TNCR.197US1 Conf. No.: 9108

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Mail Stop Office of Initial Patent Examination  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

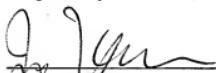
**COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE**

Dear Sir:

We disagree with the Examiner's statement of reasons for allowance as we feel the statement does not pertain to claims 125, 128 and 146.

**FILED VIA EFS**

Respectfully submitted,

  
James S. Hsue  
Reg. No. 29,545

March 18, 2008

Date

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